Device Engineering Incorporated

6031 Maple Ave. Tempe, AZ 85283 Phone: (480) 303-0822 Fax: (480) 303-0824 E-mail: admin@deiaz.com

FFATURES

- **Eight GND/OPEN discrete inputs**
 - o Internal pull up resistor with 1mA source current to prevent dry relay contacts
 - o Internal isolation diode
 - o Inputs protected from Lightning Induced Transients per DO160, Section 22 Level 3 pin injection
 - o Hysteresis provides noise immunity

3.3 V or 5 V

- 3.3 V or 5 V TTL/CMOS compatible digital IO
 - o 8 tri-state outputs
 - /CE & /OE control inputs
- VCC Logic Supply:
- VDD Analog Supply: 5 V to 18 V
- 24L TSSOP package

PIN ASSIGNMENTS

DIN1 [24 DO1 23 DO2 DIN2 $\boxed{2}$ **DEI1166** DIN3 $\boxed{3}$ 22 GND 21 DO3 DIN4 420 DO4 DIN5 519 VCC DIN6 618 DO5 DIN7 $\boxed{7}$ 17 DO6 DIN8 $\boxed{8}$ NC 9DO7 16 DO8 NC $\boxed{10}$ 15 14 GND /CE 11 VDD OE 12 13



DEI1166 **OCTAL GND/OPEN INPUT**, PARALLEL OUTPUT INTERFACE IC

©2019 Device Engineering Inc



Table 1 Pin Descriptions				
PIN	NAME	DESCRIPTION		
8-1	DIN[8:1]	Discrete Inputs. Eight Ground/Open format discrete signals. These have an internal pull-up to VDD. The threshold and hysteresis characteristics are determined by the applied VDD voltage.		
9-10	NC	Not Connected.		
11	/CE	Chip Enable Logic Input. Low input selects the device. Has an internal pull-up to VCC.		
12	/OE	Output Enable Logic Input. Low input when /CE is low will enable the tri-state outputs. Has an internal pull-up to VCC.		
13	VDD	Analog Supply. +5 to +18 V		
14	GND	Analog Ground.		
19	VCC	Logic Supply. +3.3 V or +5 V		
22	GND	Logic Ground.		
15,16,17,18,20,21,23,24	DO[8:1]	Logic Outputs. Eight tri-state data outputs.		

FUNCTIONAL DESCRIPTION

The DEI1166 is an eight-channel parallel-output discrete-to-digital interface BICMOS device. It senses eight Ground/Open discrete signals of the type commonly found in avionic systems. The data is read from the device via a parallel 3-state output.

/CE	/OE	DIN[8:1]	DO[8:1]
L	L	Open	L
L	L	Ground	Н
Н	Х	Х	High Z
Х	Н	Х	High Z



DIN INPUT

The DIN inputs are converted to logic levels via input conditioning networks and comparators. The logic signals are applied to inverting tri-state output buffers. A high level on a DIN input will result in a logic '0' on its respective DO output.

Each discrete input consists of the circuit shown in Figure 3. Each DIN signal is conditioned by the resistor / diode network and presented to the comparator IN+. The comparator IN-, and therefore the switching threshold, is developed from the VDD supply voltage. It includes positive feedback from the comparator output to provide hysteresis. Some notable features are:

- The comparator includes an RC filter to provide noise rejection of transient pulses of up to several us. Thus, there is a relatively large DIN setup time. (Refer to timing parameter tsu2).
- The inputs can withstand continuous input voltages of 40 V minimum. The isolation diode breakdown voltage is greater than 50 V. The 12 kΩ input resistor is designed to limit diode breakdown current to safe levels during lightning transient events.







Figure 5 depicts the resistance value that when applied between the input and ground, causes the comparator to switch. Lower input switching resistance values can be achieved by adding an external diode isolated pull-up resistor to the VDD (or a higher voltage) supply.



LIGHTNING PROTECTION

DIN inputs are designed to survive lightning induced transients as defined by RTCA DO160 Section 22 Level 3 pin injection Waveforms 3, 4, and 5A.



NOTE

It is possible to achieve higher level lightning immunity by adding a 1 k Ω series resistor and a Transient Voltage Suppressor (TVS) to clamp the inputs below 600 V. The 1 k Ω resistance reduces the input threshold. For example, with VDD = 15 V, the thresholds become:

Max LH threshold = 15.3 V Min HL threshold = 11.3 V

ELECTRICAL DESCRIPTION

PARAMETER	MIN	MAX	UNITS		
VCC Supply Voltage	-0.3	+7.0	V		
VDD Supply Voltage	-0.3	20	V		
Operating Temperature					
Plastic Package	-55	+125	°C		
Storage Temperature					
Plastic Package	-65	+150	°C		
Input Voltage					
DIN[8:1] Continuous	-5	+40	V		
DO160, Waveform 3, Level 3	-600	+600	V		
DO160, Waveform 4 and 5, Level 3	-300	+300	V		
Logic Inputs	-1.5	VCC + 1.5	V		
DO[8:1]		VCC + 0.5	V		
Power Dissipation @ 85 °C: (> 10 Sec)					
24L TSSOP		0.8	W		
Junction Temperature:					
Tjmax, Plastic Packages		145	С°		
ESD per JEDEC A114-A Human Body Model					
Logic and Supply pins		2000	V		
DIN pins		1000			
Peak Body Temperature		260	°C		
Notes:					
1. Voltages referenced to Ground					

Table 3 Absolute Maximum Ratings

2. Stresses above absolute maximum ratings may cause permanent damage to the device.

Table 4 Recommended Operating Conditions				
PARAMETER	SYMBOL	CONDITIONS		
Supply Voltage	VCC	5.0 V ±10%, 3.3 V ±10%		
	VDD	5.0 to 18 V		
Logic Inputs	/CE, /OE	0 to VCC		
Discrete Inputs	DIN[8:1]	0 to 40 V		
Operating Temperature				
-TES		-55 to +85 °C		
-TMS		-55 to +125 °C		

SAMBUI		TEST CONDITIONS	LIMITS		
STWDUL	FARAIVIETER	TEST CONDITIONS	MIN	MAX	
		LOGIC INPUTS AND OUTPUTS			
VIH	High level input voltage		2.0		V
VIL	Low level input voltage			0.8	V
		I _{OUT} = -40 uA	VCC – 0.1		V
V _{OH}	voltage	$VCC = 5 V \pm 10\%$ $I_{OUT} = -4.5 mA$	3.0		V
		I _{OUT} = 40 uA		0.1	V
V _{OL}	Low level output voltage	VCC = 5 V ±10% I _{OUT} = 4.5 mA		0.40	V
l _{oz}	Output 3-state leakage current	Output in Hi Impedance state. V _{OUT} = 0 V to VCC		±10	uA
IIL	Low level input current	VIN = 0 V	-50	-300	uA
Cin	Input Capacitance.			10	pF
Cout	DO pin capacitance	Output in Hi-Z state.		15	pF
		DISCRETE INPUTS VDD = +14 V			
V _{IH}	High level input voltage	-55/+85 °C -55/+125 °C	13.3 13.5		V
VIL	Low level input voltage			11.5	V
VI _{hst}	Input hysteresis voltage		0.9		V
I _{IH}	High level input current	Vin = 18 V Vin = 40 V		10 40	uA
IIL	Low level input current	Vin = 0 V	-0.7	-1.3	mA
		DISCRETE INPUTS VDD = +5.0 V			
V_{IH}	High level input voltage	-55/+85 °C -55/+125 °C	4.7 4.8		V
VIL	Low level input voltage			3.5	V
VI _{hst}	input hysteresis voltage		0.35		V
I _{IH}	High level input current	Vin = 18 V Vin = 40 V		10 40	uA
IIL	Low level input current	Vin = 0 V	-0.21	-0.43	mA
		SUPPLY CURRENT (VCC = 5.5 V, VDD = +14 V)			-1
ICC	Max quiescent logic supply current	Vin(logic) = VCC or GND DIN[8:1] = open		400	uA
IDD	Max quiescent analog supply current	Vin(logic) = VCC or GND DIN[8:1] = Open DIN[8:1] = GND		11.5 24	mA
otes: 1. Conc ratec 2. Volta	litions (unless otherwise sta d temperature range. ages referenced to Ground.	ted): VCC = 5.0 V ±10% or 3.3 V : Currents into device are positive,	±10%, VDD = 5.0 currents out of () to 18 V. Tem device are neo	nperature ative.

Table 6	AC	Electrical	Characteristics

SYMBOL	PARAMETER (VDD = +5.0V)	VCC (V)	LIMITS	UNIT
t. May	Maximum propagation dolay /CE L and /OE L to DO low	3.0	220	
t Max	r bigh (1) (2) (2) (5)	4.5	150	ns
IZH IVIAX		5.5	130	
t Max	Maximum propagation datay, (CEA as / OEA to DO ULT	3.0		
	Viaximum propagation delay, /CET of / OET to DO HI-Z.	4.5	150	ns
l _{LZ} IVIAX	FTOTT DU LOW OF HIGH. (T) (2) (3) (5)	5.5		
t Min		3.0		
t _{LH} Min	Minimum data propagation delay, DIN to DO (4) (5)	4.5	3.5	US
		5.5		
t Mov		3.0		
	Maximum data propagation delay, DIN to DO (4) (5)	4.5	630	us
t _{lH} Max		5.5		

Notes:

- 1. DO is loaded with 30 pF to GND.
- 2. DO is loaded with 5 k Ω to GND for High output, 5 k Ω to VCC for Low output.
- 3. Timing measured from VIN = 1.5 V to VOUT = 200 mV. See Figure 9.
- 4. See Figure 10. The delay is due to both the on-chip filter circuits and VDD.
- 5. Guaranteed by design.
- 6. Current flowing into device is positive. Current flowing out of device is negative. Voltages are referenced to GND.







Figure 10 Input to Output Delay

PACKAGE DESCRIPTION



Figure 11 Outline Drawing

ORDERING INFORMATION

PART NUMBER	MARK	PACKAGE	TEMPERATURE
DEI1166-TES - G	DEI1166-TES e4	24 TSSOP	-55 / +85 °C
DEI1166-TMS - G	DEI1166-TMS e4	24 TSSOP	-55 / +125 °C

DEI reserves the right to make changes to any products or specifications herein. DEI makes no warranty, representation, or guarantee regarding suitability of its products for any particular purpose.